

Si4920DY

Dual N-Channel, Logic Level, PowerTrench MOSFET

General Description

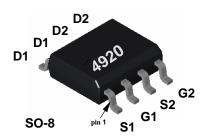
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

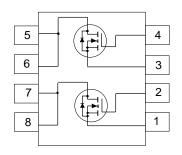
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- Fast switching speed.
- Low gate charge (typical 9 nC).
- High performance trench technology for extremely low Record.
- High power and current handling capability.







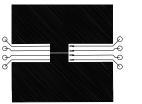
Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

Symbol	Parameter	Si4920DY	Units
V _{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	±20	V
I _D	Drain Current - Continuous (Note 1a)	6	А
	- Pulsed	20	
P _D	Power Dissipation for Single Operation (Note 1a)	2	W
	(Note 1b)	1.6	
	(Note 1c)	0.9	
T _J ,T _{STG}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

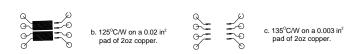
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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS	<u>.</u>			•	•	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25 °C			23		mV /°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$				1	μA
			$T_J = 55^{\circ}C$			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
	CTERISTICS (Note 2)				ı		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.5	3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I _D = 250 μA, Referenced	I _D = 250 μA, Referenced to 25 °C		-4		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 6 \text{ A}$			0.023	0.028	Ω
()			T _J =125°C		0.036	0.044	
		$V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$			0.029	0.035	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \ V_{DS} = 5 \text{ V}$		20			Α
g _{FS}	Forward Transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 6 \text{ A}$			18		S
DYNAMIC (CHARACTERISTICS				l .		
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			830		pF
C _{oss}	Output Capacitance				185		pF
C _{rss}	Reverse Transfer Capacitance				80		pF
SWITCHING	CHARACTERISTICS (Note 2)			1	1		_
$\mathbf{t}_{D(on)}$	Turn - On Delay Time	$V_{DS} = 15 \text{ V}, I_{D} = 1 \text{ A}$			6	12	ns
t _r	Turn - On Rise Time	$V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$			10	18	ns
t _{D(off)}	Turn - Off Delay Time				18	29	ns
t,	Turn - Off Fall Time				5	12	ns
Q_g	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 7.5 \text{ A},$			9	13	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 5 V			2.8		nC
Q_{gd}	Gate-Drain Charge				3.1		nC
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAX	KIMUM RATINGS					
Is	Maximum Continuous Drain-Source Diode Forward Current					1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A} \text{ (Note 2)}$			0.73	1.2	V

1. $R_{g,u,i}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{g,c,i}$ is guaranteed by design while $R_{g,c,i}$ is determined by the user's board design.



a. 78°C/W on a 0.5 in² pad of 2oz copper.





Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

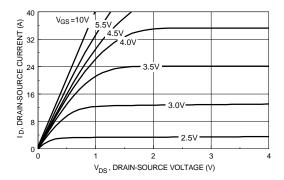


Figure 1. On-Region Characteristics.

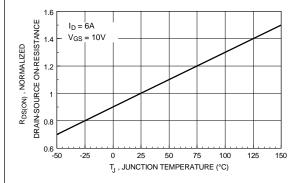


Figure 3. On-Resistance Variation with Temperature.

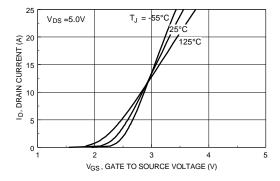


Figure 5. Transfer Characteristics.

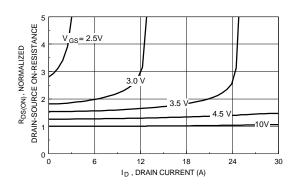


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

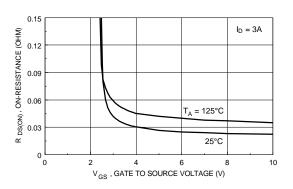


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

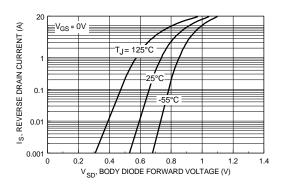


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics

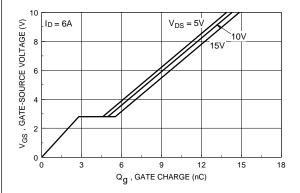
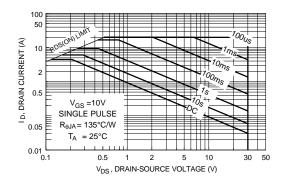


Figure 7. Gate Charge Characteristics.





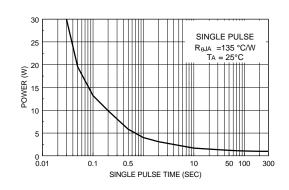


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

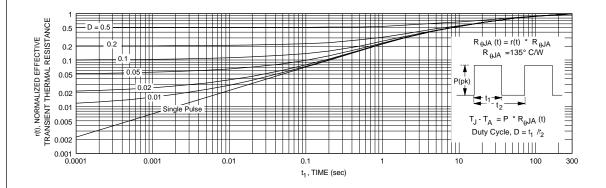


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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